Atomic Resolution Analytical Electron Microscope

## JEM-ARM200F

## **NEOARM**



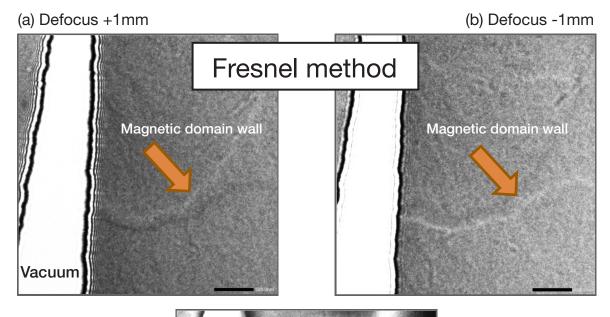
Data set for observing ferromagnetic samples.

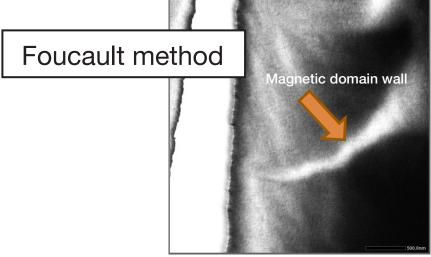
The mode has no magnetic field around samples.



## Lorentz observation mode

Data set for observation under no magnetic field around sample





Acc Voltage: 200kV Lorentz mode: x15k Sample: Ni thin film

Examples: Fresnel & Foucault methods for observations of magnetic domain in Ni thin film

Specification:	Magnification	
Ranges	STEM Cs corrector configuration	TEM or Double Cs corrector configuration
LM1	x50 to 1500 (8 steps)	x50 to 1500 (8 steps)
LM2	x2000 to 6000 (6 steps)	x2000 to 6000 (6 steps)
LM3	x8000 to 50k (6 steps)	x8000 to 80k (6 steps)

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